Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination | BAYAN ET AL. | Examiner | Art Unit | Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0124508 A1	07-2004	Tan et al.	257/675
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